# Quad 2-input NAND 30 $\Omega$ line driver (open collector)

### 74F3038

#### **FEATURES**

- 30Ω line driver
- 160mA output drive capability
- High speed
- Facilitates incident wave switching
- 3nh lead inductance each on V<sub>CC</sub> and GND when both side pins are used

#### DESCRIPTION

The 74F3038 is a high current Open-Collector Line Driver composed of four 2-input NAND gates. It has been designed to deal with the transmission line effects of PC boards which appear when fast edge rates are used.

The 74F3038 can sink 160mA with a  $V_{CC}$  as low as 4.5V. This guarantees incident wave switching with  $V_{OL}$  not more than 0.8V while driving impedances as low as 30 $\Omega$ . This is applicable with any combination of outputs using continuous duty.

The AC specifications for the 74F3038 were determined using the standard FAST load for open-collector parts of 50pF capacitance, a 500 $\Omega$  pull-up resistor and a 500 $\Omega$  pull-down resistor. (See Test Circuit).

Reducing the load resistors to 100 $\Omega$  will decrease the t<sub>PLH</sub> propagation delay by approximately 50% while increasing t<sub>PHL</sub> only slightly. The graph of typical propagation delay versus load resistor (see AC Characteristics section for Graph) shows a spline fit curve from four measured data points, R<sub>L</sub> = 30 $\Omega$ , R<sub>L</sub> = 100 $\Omega$ , R<sub>L</sub> = 300 $\Omega$ , and R<sub>L</sub> = 500 $\Omega$ .

### INPUT AND OUTPUT LOADING AND FAN-OUT TABLE

PINS	VINS DESCRIPTION 74F(U.L.) HIGH/LOW		LOAD VALUE HIGH/LOW
Dna, Dnb	Data inputs	1.0/1.0	20µA/0.6mA
Qn	Data outputs	OC/266	OC/160mA

NOTE: One (1.0) FAST unit load is defined as: 20µA in the High state and 0.6mA in the Low state. OC = Open Collector.

#### LOGIC SYMBOL



### **IEC/IEEE SYMBOL**



PIN CONFIGURATIO	ON	
D0a 1		16 Q3
D0b 2		15 D3b
Q0 3		14 D3a
GND 4		13 V <sub>CC</sub>
GND 5		12 V <sub>CC</sub>
Q1 6		11 D2a
D1a 7		10 D2b
D1b 8		9 Q2
		SF00570

TYPE	TYPICAL PROPAGATION DELAY	TYPICAL SUPPLY CURRENT (TOTAL)
74F3038	6.0ns	17mA

#### **ORDERING INFORMATION**

DESCRIPTION	$\begin{array}{l} \text{COMMERCIAL RANGE} \\ \text{V}_{\text{CC}} = 5\text{V} \pm 10\%, \\ \text{T}_{\text{amb}} = 0^{\circ}\text{C to} + 70^{\circ}\text{C} \end{array}$	PACKAGE DRAWING NUMBER	
16-pin Plastic DIP	N74F3038N	SOT38-4	
16-pin Plastic SOL	N74F3038D	SOT162-1	

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#### LOGIC DIAGRAM



#### **FUNCTION TABLE**

INPUTS				
Dnb	Qn			
L	Н			
н	н			
L	Н			
н	L			
	Dnb L H L H			

H = High voltage level L = Low voltage level

#### **ABSOLUTE MAXIMUM RATINGS**

(Operation beyond the limits set forth in this table may impair the useful life of the device. Unless otherwise noted these limits are over the operating free-air temperature range.)

SYMBOL	PARAMETER	RATING	UNIT
V <sub>CC</sub>	Supply voltage	-0.5 to +7.0	V
V <sub>IN</sub>	Input voltage	-0.5 to +7.0	V
I <sub>IN</sub>	Input current	-30 to +5	mA
V <sub>OUT</sub>	Voltage applied to output in High output state	–0.5 to $V_{CC}$	V
I <sub>OUT</sub>	Current applied to output in Low output state	320	mA
T <sub>amb</sub>	Operating free-air temperature range	0 to +70	°C
T <sub>stg</sub>	Storage temperature range	-65 to +150	°C

### **RECOMMENDED OPERATING CONDITIONS**

SYMBOL	DADAMETED				
	PARAMETER	MIN	NOM	MAX	UNIT
V <sub>CC</sub>	Supply voltage	4.5	5.0	5.5	V
V <sub>IH</sub>	High-level input voltage	2.0			V
VIL	Low-level input voltage			0.8	V
I <sub>IK</sub>	Input clamp current			-18	mA
V <sub>OH</sub>	High-level output voltage			4.5	V
I <sub>OL</sub>	Low-level output current			160	mA
T <sub>amb</sub>	Operating free-air temperature range	0		+70	°C

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#### DC ELECTRICAL CHARACTERISTICS

(Over recommended operating free-air temperature range unless otherwise noted.)

	PARAMETER		TEST CONDITIONS <sup>1</sup>			LIMITS			LINUT
STMBOL						MIN	TYP <sup>2</sup>	MAX	UNIT
I <sub>ОН</sub>	High-level output current		$V_{CC} = MIN, V_{II}$	= MAX, V <sub>IH</sub> = M	IN, V <sub>OH</sub> = MAX			250	μA
Ve			$V_{CC} = MIN$	I <sub>OL</sub> = 100mA	±10% V <sub>CC</sub>		0.42	0.55	V
V <sub>OL</sub> Low-level output current			$V_{IH} = MIN$	$I_{OL} = 160 \text{mA}^3$	$\pm 5\% V_{CC}$			0.80	V
V <sub>IK</sub>	Input clamp voltage		$V_{CC} = MIN, I_I = I_{IK}$				-0.73	-1.2	V
I	Input current at maximun voltage	n input	V <sub>CC</sub> = MAX, V <sub>I</sub> = 7.0V					100	μΑ
I <sub>IH</sub>	High-level input current		$V_{CC} = MAX, V_I = 2.7V$				20	μA	
IIL	Low-level input current		$V_{CC} = MAX, V_I = 0.5V$				-0.6	mA	
	Supply current (total)	I <sub>CCH</sub>		- MAY	V <sub>IN</sub> = GND		3.5	6.0	mA
ICC	Supply current (total)	ICCL	VCC ■		V <sub>IN</sub> = 4.5V		30	40	mA

#### NOTES:

1. For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable type.

2. All typical values are at  $V_{CC} = 5V$ ,  $T_{amb} = 25^{\circ}C$ . 3.  $I_{OL1}$  is the current necessary to guarantee the High to Low transition in a 30 $\Omega$  transmission line on the incident wave.

#### **AC ELECTRICAL CHARACTERISTICS**

			LIMITS					
SYMBOL	PARAMETER	R TEST CONDITION	$\begin{array}{l} {T_{amb}=+25^\circ {C}}\\ {V_{{CC}}=+5.0 {V}}\\ {C_{L}=50 {pF},  {R}_{L}=500 \Omega} \end{array}$			$\begin{array}{l} {T_{amb}} = 0^{\circ}{C} \ to \ +70^{\circ}{C} \\ {V_{CC}} = +5.0V \pm 10\% \\ {C_{L}} = 50pF, \ R_{L} = 500\Omega \end{array}$		UNIT
			MIN	TYP	MAX	MIN	MAX	
t <sub>PLH</sub> t <sub>PHL</sub>	Propagation delay Dna, Dnb to Qn	Waveform 1	6.0 1.0	8.5 2.0	11.5 5.0	6.0 1.0	12.0 5.0	ns

#### **AC WAVEFORMS**

For all waveforms,  $V_M = 1.5V$ .



Waveform 1. Propagation Delay for Inputs to Output

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#### Note

1. Plastic or metal protrusions of 0.15 mm maximum per side are not included.

OUTLINE		REFER	EUR	OPEAN	
VERSION	IEC	JEDEC	EIAJ	PROJ	ECTION
SOT162-1	075E03	MS-013AA			30